DORNPACKAGE

(TOP VIEW)

- Contains Six D-Type Flip-Flops With Single-Rail Outputs
- Applications Include:

 Buffer/Storage Registers
 Shift Registers

 Pattern Generators
- Buffered Common Enable Input
- Package Options Include Plastic Small-Outline Packages and Standard Plastic 300-mil DIPs

CLKEN 16 V_{CC} 1Q [15 ¶ 6Q 2 1D [14 🛮 6D 3 2D 13 ∏ 5D 2Q 12 5Q 5 3D [11 **∏** 4D 6 3Q [10 ¶ 4Q GND [8 9 CLK

description

The SN74F378 is a positive-edge-triggered D-type flip-flop with a clock enable (CLKEN) input. The SN74F378 is similar to the SN74F174 but features a common clock enable instead of a common clear.

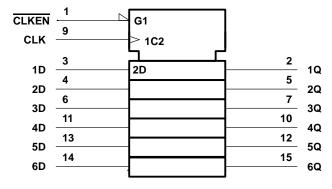
Information at the data (D) inputs meeting the setup time requirements is transferred to the Q outputs on the positive-going edge of the clock pulse if CLKEN is low. Clock triggering occurs at a particular voltage level and is not directly related to the positive-going pulse. When the clock (CLK) input is at either the high or low level, the D-input signal has no effect at the output.

The SN74F378 is characterized for operation from 0°C to 70°C.

FUNCTION TABLE (each flip-flop)

INPUTS			OUTPUT
CLKEN	CLK	D	Q
Н	Х	Х	Q_0
L	\uparrow	Н	Н
L	\uparrow	L	L
X	L	Χ	Q_0

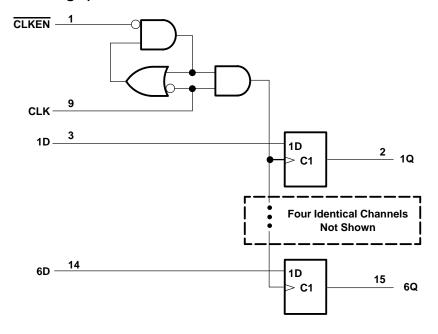
logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	0.5 V to 7 V
Input voltage range, V _I (see Note 1)	1.2 V to 7 V
Input current range	–30 mA to 5 mA
Voltage range applied to any output in the high state	0.5 V to V _{CC}
Current into any output in the low state	40 mA
Operating free-air temperature range	0°C to 70°C
Storage temperature range	−65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input-voltage ratings may be exceeded provided the input-current ratings are observed.

recommended operating conditions

		MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	V
VIH	High-level input voltage	2			V
V_{IL}	Low-level input voltage			8.0	V
liK	Input clamp current			-18	mA
ІОН	High-level output current			-1	mA
loL	Low-level output current			20	mA
TA	Operating free-air temperature	0		70	°C



electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS			TYP [†]	MAX	UNIT
VIK	$V_{CC} = 4.5 \text{ V},$	$I_1 = -18 \text{ mA}$			- 1.2	V
V	$V_{CC} = 4.5 \text{ V},$	$I_{OH} = -1 \text{ mA}$	2.5	3.4		V
VOH	$V_{CC} = 4.75 \text{ V},$	$I_{OH} = -1 \text{ mA}$	2.7			٧
VOL	$V_{CC} = 4.5 \text{ V},$	$I_{OL} = 20 \text{ mA}$		0.3	0.5	V
lį	$V_{CC} = 5.5 \text{ V},$	V _I = 7 V			0.1	mA
I _{IH}	$V_{CC} = 5.5 \text{ V},$	V _I = 2.7 V			20	μΑ
I _{IL}	$V_{CC} = 5.5 \text{ V},$	V _I = 0.5 V			- 0.6	mA
I _{OS} ‡	$V_{CC} = 5.5 \text{ V},$	V _O = 0	- 60		- 150	mA
Icc	V _{CC} = 5.5 V,	See Note 2		30	45	mA

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

timing requirements

			V _{CC} =	V _{CC} = 5 V, T _A = 25°C		V _{CC} = 4.5 V to 5.5 V, T _A = MIN to MAX§	
			MIN	MAX	MIN	MAX	
fclock	Clock frequency		0	110	0	110	MHz
	Dides direction	CLK high	4		4		ns
t _W Pulse durati	Pulse duration	CLK low	6		6		
		Data high or low	5		5		ns
t _{SU} Setup time before CLK↑	Setup time before CLK↑	CLKEN high	3.5		3.5		
		CLKEN low	5		5		
th Hold time after C	Hald for a first OLK	Data high or low	1		1		
	Hold time after CLK	CLKEN high or low	0		0		ns

switching characteristics (see Note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	C _L R _L	C = 5 V, = 50 pF = 500 Ω = 25°C	,	V _{CC} = 4.5 C _L = 50 pl R _L = 500 Ω T _A = MIN 1	2,	UNIT
			MIN	TYP	MAX	MIN	MAX	
fmax			110	125		110		MHz
tPLH	CLK	Any O	3.3	4.5	6.1	3.1	6.7	20
^t PHL	OLK	Any Q	3	4.2	6	2.9	6.1	ns

§ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. NOTE 3: Load circuits and waveforms are shown in Section 1.



[‡] Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

NOTE 2: I_{CC} is measured with all outputs open, all data inputs and the enable input grounded, and the clock input at 4.5 V after being momentarily grounded.

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